# Polymer light-emitting field-effect transistors with hole mobility exceeding $1\ cm^2\ V^{-1}\ s^{-1}$

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## Abstract

The vast majority of conjugated polymer-based light emitting field-effect transistors (LEFETs) are characterized by low charge carrier mobilities typically in the range  $10^{-5}$  to  $10^{-3}$  cm<sup>2</sup> V<sup>-1</sup> s<sup>-1</sup> range. Fast carrier transport is a highly desirable characteristic for high frequency LEFET operation and, potentially, for use in electrically-pumped lasers. Unfortunately, high mobility organic semiconductors are often characterised by strong intermolecular  $\pi$ - $\pi$  interactions that reduce luminescence. Development of new materials and/or device concepts that overcome this hurdle are therefore required. We report single organic semiconductor layer, light-emitting transistors that combine the highest hole mobilities reported to date for any polymer-based LEFET, with encouraging light emission characteristics. We achieve this in a single polymer layer LEFET, which was further enhanced through the use of a small-molecule/conjugated polymer blend system that possesses a film microstructure which supports enhanced charge carrier mobility (3.2 cm<sup>2</sup> V<sup>-1</sup> s<sup>-1</sup>) and promising light emission characteristics (1600 cd m<sup>-2</sup>) as compared to polymer-only based LEFETs. This simple approach represents an attractive strategy to further advance the performance of solution-processed LEFETs.

The performance of organic field effect transistors (OFETs) has been improving rapidly in recent years and charge carrier mobilities are now higher than amorphous silicon (Si) (1-4), offering performance adequate for various electronic and display applications. In addition, the versatility of organic semiconductors has allowed development of interesting bifunctional devices such as light-sensing (LSFETs) (5-6) and light-emitting (LEFETs) FETs (7-12). The demonstration of the first organic LEFETs in 2003 instigated a major research effort focused on the development of novel device architectures (13-19) and high mobility light-emitting materials (14,20) with a significant potential for a wider range of applications including, active matrix colour displays, biomedical sensors, integrated circuits and in communication devices. Furthermore, it was argued that for the development of electrically-pumped organic laser diodes, a similar materials optimisation may be required (1, 21). Unfortunately, combining high charge carrier mobility and efficient light emission in organic materials has proven challenging (21-25), because on one hand the reduction of inter-chain interactions benefits the luminescence efficiency but on the other hand it suppresses charge transport (26). Currently, best-performing solution-processed polymer LEFETs show carrier mobilities significantly lower (10<sup>-3</sup> to 10<sup>-5</sup> cm<sup>2</sup> V<sup>-1</sup> s<sup>-1</sup>) than small-molecule based LEFETs ( $\approx 1 \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$ ) (14,15,25) but with significantly higher electroluminescence efficiencies (11,13). To address this challenge, multilayer channel LEFET architectures have also been developed (13, 18-19) with primary aim to decouple the charge transport process from light emission. Unfortunately, multilayer channels require complex processing often resulting to poor efficiencies due to imbalance charge transport. The development of novel organic semiconductor systems that combine high mobility with efficient light emission characteristics is therefore timely for the broader area of LEFETs.

Recently, high mobility OFETs have been fabricated using binary and ternary smallmolecule/conjugated polymer blends (27-31). Blend OFETs combine the advantageous properties of solution processing with superior charge transport characteristics that compare favorably with the best-in-class OFETs reported to date (29,31). Motivated by the blend approach, we wondered whether carefully designed blend channels can indeed be implemented in LEFETs. To test this hypothesis we combined the high hole mobility (>20 cm<sup>2</sup> V<sup>-1</sup> s<sup>-1</sup>) (29,30), and solution processable, small-molecule 2,7-dioctyl[1]-benzothieno[3,2b][1]benzothiophene (C<sub>8</sub>-BTBT) (4), with the polymeric semiconductor poly[[6,6,12,12tetrakis(4-hexadecylphenyl)-6,12-dihydroindeno[1,2-b]indeno[2',1':4,5]thieno[2,3-d] thiophene-2,8-diyl]thieno[3,2-b]thiophene-2,5-diyl] (PDITTTT) (35) to form the blend channel layer. C<sub>8</sub>-BTBT is a wide band gap material ( $\approx 3.6 \text{ eV}$ ) known for its ultra-high hole mobility and non-emissive characteristics (photoluminescence quantum efficiency, PLQE, of  $\approx 0.5\%$ ). Therefore, its application in LEFETs will most certainly require the presence of an emissive component that can be excited via Förster energy transfer during device operation (30-31). PDITTTT, on the other hand (35), is similar to other donor-acceptor copolymers reported previously and used extensively in organic solar cells (36). Surprisingly, we found that C<sub>8</sub>-BTBT:PDITTTT blend LEFETs exhibit hole mobility ( $\mu_h$ ) of  $\approx 3 \text{ cm}^2 \text{ V}^{-1}\text{s}^{-1}$  -a value higher than any previously reported LEFETs (8-11)- this combined with high electroluminance (1600 cd m<sup>-2</sup>) exceeds the state-of-the-art performance in solution-processed LEFETs (8-13) and even LEFETs made of organic single crystals (25). Furthermore, the top-gate architecture employed in combination with the fluoropolymer gate dielectric CYTOP<sup>TM</sup>, results in LEFETs with enhanced environmental stability.

Fig. 1a shows the chemical structure of PDITTTT with its extended fused-ring sequence driving a high degree of molecular planarity. The normalised UV-Vis absorption and photoluminescence (PL) spectra of a PDITTTT thin film (534 nm, pumped at 405 nm) before and after annealing at 120 °C are shown in Fig. 1b, while normalised UV-Vis absorption and PL spectra of the C<sub>8</sub>-BTBT film (367 nm, pumped at 340 nm) before and after annealing at 120 °C are shown in Fig. S1 in Supporting Information. Fig. 1c & 1d show, the molecular structure of C<sub>8</sub>-BTBT along with the normalised UV-vis absorption and PL spectra of the C<sub>8</sub>-BTBT:PDITTT blend film (534 nm, pumped at 405 nm) before and after annealing at 120 °C. The blend ratio was optimised in terms of transistors performance at 1:3 (by weight) of small molecule to polymer, further details on solution processing is presented in the Experimental Section. The vibronic absorption and PL of the neat PDITTTT films show that its long side chains are not adversely impacting the planarity of the molecule, nor creating high levels of disorder within the film. This structure is preserved with the addition of C<sub>8</sub>-BTBT, however the scattering tail seen in the 'As Spun' blend film suggests a rougher surface than the neat PDITTTT film. This feature is retained post annealing, but to a much lesser degree, indicating that the thermal processing has helped to smooth the surface of the blend layer. The C<sub>8</sub>-BTBT absorption peak at 359 nm (given in Supporting Information, Fig. 1d and Fig. S1), is clearly seen in the blend absorption, however its emission at 367 nm (Fig. 1d and Fig. S1) is not visible, due to Förster energy transfer to the PDITTTT chromophore, resulting in a PL spectrum consistent with neat the PDITTTT film (534 nm). The relatively small spectral overlap in the PL of C<sub>8</sub>-BTBT and PDITTTT highlights the possibility of replacing PDITTTT with more

absorbing units/materials in order to improve Förster energy transfer. The PLQE of PDITTTT and blend films, pumped at 405nm, were 11.7 %, and 13.3 % respectively. The PLQE of C<sub>8</sub>-BTBT film (pumped at 340 nm) was  $\approx 0.5$  %. The PLQE and absorption parameters for the various materials studied are provided **Fig. S2, S3** and **Table S1** in **Supporting Information**.

It is known that reducing the refractive indices of the constituent layers in an organic light emitting device can enhance light extraction (37). Lowering the refractive index of the organic layers can thus reduce light coupling to the thin-film guided modes and suppress Fresnel reflection from the boundaries (38). As determined by variable angle spectroscopic ellipsometry (VASE), the refractive index of C<sub>8</sub>-BTBT and PDITTTT were 1.6 and 2 at 550 nm (see **Figs. S4** and **S5** in Supporting Information). The refractive index was reduced to 1.8 at 550 nm (**Fig. S6**, in **Supporting Information**) after mixing the PDITTTT with C<sub>8</sub>-BTBT, which could result in factor of 1.2 increase of  $\eta_{out}$  at 550 nm from crude calculation ( $\eta_{out} = 1/2n^2$ , where *n* is the refractive index of the material in which the light is generated).

To further investigate the optical properties of thermally annealed (120 °C) PDITTTT and C<sub>8</sub>-BTBT:PDITTTT blend films, time-resolved PL (TRPL) (pumped at 405 nm) measurements were performed (**Fig. 2a**, **Fig. S7** and **S8**). A bi-exponential decay was observed for both films with slightly longer decay times for the C<sub>8</sub>-BTBT:PDITTTT blend ( $t_1 \approx 0.090$ ns and  $t_2 \approx 1.00$  ns) than for the pristine PDITTTT ( $\tau_1 \approx 0.083$  and  $\tau_2 \approx 0.89$ ). The TRPL curves for the pristine C<sub>8</sub>-BTBT film (absorption edge  $\approx 340$  nm, PL<sub> $\lambda$ max</sub>  $\approx 370$  nm) could not be recorded due to instrument limitation.

The microstructure of PDITTTT and C<sub>8</sub>-BTBT:PDITTTT blend films were also studied using atomic force microscopy (AFM) and X-ray diffraction (XRD) measurements (**Fig. 2b**, **2c** and **2d**). From the AFM images we observe that the PDITTTT films appear smooth and largely disordered with no evidence of strong surface features (**Fig. 2b** and **Fig. S9**). Blend films, on the other hand, appear polycrystalline (**Fig. 2c**). The polycrystalline nature of the blend film is attributed to the phase separation of C<sub>8</sub>-BTBT to the surface of the blend film and the formation of large polycrystalline domains in the top layers, in accordance with previous results (26-29). XRD measurements were obtained in the Bragg-Brentano geometry for C<sub>8</sub>-BTBT, PDITTTT and C<sub>8</sub>-BTBT:PDITTTT blend films (**Figure 2d**). The PDITTTT film was found to be amorphous without noticeable diffraction peaks. Conversely, C<sub>8</sub>-BTBT and C<sub>8</sub>- BTBT:PDITTTT blend samples exhibit diffraction patterns that are broadly consistent with the  $C_8$ -BTBT powder diffractogram (39). For  $C_8$ -BTBT, the stronger diffraction peaks are observed at around 6° and 9° and correspond to (00h) planes, which is typical for the formation of rod-like crystals. In the case of the blend film, the (020) peak also emerges, which is usually a manifestation of strain (40). This suggestion is supported by the evident shift of the (002) peak upon blending (see inset in Fig. 2d) which confirms a substantial deformation of the C<sub>8</sub>-BTBT crystal cell. In addition, the shift is accompanied by changes in the profile of this peak, namely a reduced intensity and increased broadening. The calculated values of microstrain, as extracted by fitting the three prominent (002) diffraction peaks to Voigt curves (with both Lorentzian and Gaussian contributions) were exceptionally small and similar across both samples. This suggests that the deformation of the C<sub>8</sub>-BTBT within the blend is of a hydrostatic nature and does not cause any additional structural defects, which were assigned to reduced lateral size of organic molecule lamellae in contrast to the case of dif-TES-ADT as previously reported (4). Finally, the vertical grain size ( $G_z$ ) was calculated to be  $\approx 69$  nm for C<sub>8</sub>-BTBT *versus*  $\approx$ 38 nm for the binary blend. As the lateral lamellar size is not affected by blending, it seems that the polymer is distributed in between of the wide  $C_8$ -BTBT lamellae along the zdirection resembling an intercalation process.

The electrical properties of the polymer and blend films were evaluated using bottomcontact, top-gate (BC-TG) FETs (**Fig. 3**). Gold source-drain (S-D) electrodes were treated with the self-assembled monolayer (SAM) 2,3,4,5,6-Pentafluorothiophenol (PFBT) to improve hole injection (41). The organic semiconducting materials and the dielectric layer were then deposited via spin coating followed by thermal annealing at 120 °C in a nitrogen filled glovebox. The device fabrication was completed with the deposition of Al gate electrodes. Further details of material preparation and fabrication methods can be found in the *Materials and Methods* section.

A representative set of PDITTTT transistor transfer characteristics (channel length (L) and width (W) of 50 and 1000  $\mu$ m) is shown in **Fig. 3b**. The devices exhibit excellent hysteresis-free *p*-channel operation in both linear (V<sub>DS</sub> = - 20 V) and saturation (V<sub>DS</sub> = - 100 V) regimes with channel current ON/OFF ratio >10<sup>5</sup>. The electrical output characteristics for this particular device are shown in **Fig. 3c**, with saturation regime hole mobility  $\mu_{h,sat} \approx 1 \text{ cm}^2$  V<sup>-1</sup> s<sup>-1</sup>. A similar device architecture was used to fabricate the C<sub>8</sub>-BTBT:PDITTTT blend transistors (**Fig. 3**) and the corresponding transfer and output characteristics are shown in **Fig.** 

**3d** and **3e**. In the blend films an emergence of the small and insignificant hysteresis is observed, with a substantially lower ON/OFF ratio (>10<sup>3</sup>) than for the PDITTTT-only devices, this might be due to increased conducting paths in blend films and rougher films. However, saturation regime hole mobility  $\mu_{h,sat} \approx 1.6 \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$  is slightly higher. To exclude any overestimation in the FET mobility calculations (42-43), we further analysed the calculated mobility values following the method proposed by Choi *et al.* (43) (see **Supplementary Information**). The associated reliability factor was calculated and used to determine FET ideality-corrected effective mobilities for both devices, yielding  $\mu_{h,eff} \approx 0.63$  and 0.83 cm<sup>2</sup> V<sup>-1</sup> s<sup>-1</sup> for polymer and blend FETs, respectively (**Table S2** in **Supplementary Information**).

In a similar manner, polymer and blend LEFETs were fabricated in BC-TG architecture (Fig. 4a) but this time using asymmetric S-D electrodes. PFBT-functionalised Au was used as hole injecting electrode, whilst a combination of caesium carbonate/silver (Cs<sub>2</sub>CO<sub>3</sub>/Ag) was used for electron injection. The pristine PDITTTT LEFETs exhibited strictly unipolar pchannel behaviour with a current ON/OFF ratio of >10<sup>5</sup> (Fig. 4b) and  $\mu_{h,sat} \approx 0.8 \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$ . Despite the absence of clear electron accumulation within the channel, electron injection from the Cs<sub>2</sub>CO<sub>3</sub>/Ag electrode into the lowest unoccupied molecular orbital (LUMO) energy state of PDITTTT (-3 eV) does take place as evident by the light emission occurring in close proximity to the electron injecting electrode. However, we determined electron mobilities in space charge limited current scenario in a diode configuration of glass/Al/Cs<sub>2</sub>CO<sub>3</sub>/(polymer or blend)/Cs<sub>2</sub>CO<sub>3</sub>/Al) which were  $\approx 5.6 \times 10^{-8}$  cm<sup>2</sup> V<sup>-1</sup> s<sup>-1</sup> and  $6 \times 10^{-8}$  cm<sup>2</sup> V<sup>-1</sup> s<sup>-1</sup> for PDITTTT and C8:BTBT:PDITTTT films, respectively (Fig. S10). The corresponding output characteristics are shown in Fig. 4d and 4e. Similarly, p-channel dominated operation was observed for the C<sub>8</sub>-BTBT:PDITTTT blend transistors (**Fig. 4c**) but with a significantly higher  $\mu_{h,sat}$  (7 cm<sup>2</sup> V<sup>-1</sup> s<sup>-1</sup>) and a lower current ON/OFF ratio ( $\approx 10^3$ ). The output characteristics of a representative blend LEFET are shown in Fig. 4f. Finally, the transistors' mobility reliability factors were also calculated yielding values for  $\mu_{h,eff}$  of 0.42 and 3.2 cm<sup>2</sup> V<sup>-1</sup> s<sup>-1</sup> for the pristine PDITTTT and C<sub>8</sub>-BTBT:PDITTTT based devices, respectively (Supplementary Information, Table **S1**).

Fig. 5a and 5b show, respectively, the luminance, L, (cd/m<sup>2</sup>) and external quantum efficiency, EQE (%), for PDITTTT LEFETs as a function of gate-source voltage (V<sub>GS</sub>). In the case of top emission, L increases for  $|V_{GS}| > -18V$  and reaches  $\approx 100$  cd m<sup>-2</sup> at V<sub>GS</sub> = -150 V, with an EQE of  $\approx 1.3 \times 10^{-2}$  %. For bottom emission, L  $\approx 300$  cd m<sup>-2</sup> at V<sub>GS</sub> = -150 V, with the

EQE =  $3.1 \times 10^{-2}$  %. The improved performance in bottom-emission is mainly due to higher transmittance (~89%, see Fig. S11), as compared to the reflective semi-transparent Al gate electrode (~20%). Fig. 5c and 5d show the corresponding L and EQE characteristics for the C<sub>8</sub>-BTBT:PDITTTT blend LEFETs where L  $\approx$  500 cd m<sup>-2</sup> (EQE = 1×10<sup>-2</sup> %) measured for top emission and L  $\approx$  1700 cd m<sup>-2</sup> (EQE = 4×10<sup>-2</sup> %) measured for bottom emission at V<sub>GS</sub> = -150 V. Therefore, blend LEFETs clearly show enhanced light-emission than pristine polymer LEFETs in addition to their enhanced electrical performance. Finally, the maximum current densities (hole) passing through the recombination zone for polymer only and blend devices were calculated to be 1.6 A/cm<sup>2</sup> and 3.6 A/cm<sup>2</sup>, respectively (Fig. S12 and S13). These results are summarized in Table 1 together with a performance comparison against previously reported polymer LEFETs found in the literature. Although the improved performance in our LEFETs arises from extended fused-ring sequence in PDITTTT molecules providing a high degree of planarity and order within the films, and the long side chains provide spacing to prevent quenching of photoluminescence, while these features are preserved in neat and blend film. However, on the basis of these results we conclude that the limiting factor for efficient light emission in this type of LEFETs is the transport of electrons, which is subject of ongoing research in material development. Simultaneous improvement of electron injection and ambipolar charge transport is essential for realising ideal LEFETs.

**Fig. 5e** shows optical images of two LEFETs based on the pristine polymer and blend during operation. The emission area appears as a narrow zone in close proximity to the electron injecting Cs<sub>2</sub>CO<sub>3</sub>/Ag electrode, which is indicative of the highly imbalanced charge transport discussed above. The width of emission zone was estimated at around  $\approx 6 \,\mu m$  for polymer only LEFET and  $\approx 14 \,\mu m$  for blend LEFET (see **Fig. S14** and **Fig S15** in **Supporting Information**). The broader emission pattern seen in the blend LEFET may well be attributed to the non-uniform and highly texture surface of the blend channel rather than being an intrinsic device property. Moreover, the electroluminescence (EL) spectrum for a pristine polymer and a blend LEFET measured from the top, are shown as black lines in **Fig. 5f** and **Fig. 5g**, respectively. Both emission spectra appear identical with the characteristic vibronic features largely matching those seen in the corresponding PL spectra (blue lines).

The operation of these LEFETs can be understood by considering the energy levels of the materials used to construct them (**Fig. S16**). Negative  $V_{GS}$  (< 0 V) and  $V_{DS}$  (< 0 V) helps to

inject and accumulate holes at the polymer / CYTOP or blend / CYTOP interface. The mobile holes move across the LEFET channel and recombine with injected electrons in close proximity to the drain electrode (i.e.  $Cs_2CO_3$  / Ag) as evident by the microscope images shown in **Fig. 5e**. The internal quantum efficiency or otherwise known as recombination efficiency was also calculated using the measured photoluminescence quantum yield (PLQE) values for the pristine polymer ( $\approx$ 11.7 %) and blend ( $\approx$ 13.3 %) films, yielding modest values of 5.8 % and 5.1 %, respectively, measured at the highest operating voltages. Importantly, the use of CYTOP appears to be highly advantageous in terms of environmental stability of the LEFETs since all devices could be stored in ambient air for over 4 weeks before small performance degradation was observed ( $\approx$ 3%, shown in **Fig. S17**).

In summary, we have demonstrated PDITTTT polymer and binary C<sub>8</sub>-BTBT: PDITTTT blend based transistors and light-emitting transistors with maximum hole mobility values ( $3.2 \text{ cm}^2 \text{V}^{-1} \text{s}^{-1}$ ) significantly higher than any previously reported polymer-based LEFETs. Carefully engineered devices exhibit green light emission with modest brightness levels (1600 cd/m<sup>2</sup>) and an internal quantum efficiency of ~ 5 %. Importantly, the top-gate LEFETs exhibit long shelf lifetimes, a characteristic attributed to the use of CYTOP as the gate dielectric. These results present a significant step towards LEFETs that combine high carrier mobility with appreciable light emitting characteristics, hence making small molecule/polymer blends an attractive option for numerous opto-electronic applications.

#### **Materials and Methods**

Solution preparation: Conjugated polymer PDITTTT (35), containing diindeno-thieno [3,2b]thiophene based polycyclic repeat units with a MW of 242k and a polydispersity of 2.85 as measured by GPC against polystyrene standards, was obtained from Merck GMBH. A solution of 10 mg mL<sup>-1</sup> of PDITTT was prepared using anhydrous 1,2,3,4-tetrahydronaphthalene (purchased by Sigma-Aldrich) and 10 mg mL<sup>-1</sup> C<sub>8</sub>-BTBT (purchased by One-Material) in anhydrous chlorobenzene where spin coated at 2000 rpm for 30 seconds. For the C<sub>8</sub>-BTBT:PDITTTT blend formulations, 20 mg mL<sup>-1</sup> solutions of the small molecule in chlorobenzene were mixed in a 1:3 ratio with 15 mg mL<sup>-1</sup> polymer solutions in 1,2,3,4tetrahydronaphthalene and spin-coated at 2000 rpm for 30 seconds.

*Transistor Fabrication:* Bottom-contact, top-gate (BC-TG) FETs and LEFETs were fabricated on glass substrates pre-cleaned in DECON 90 detergent solution, followed by sonication in

acetone and isopropanol. Source and drain electrodes were deposited by shadow-masked thermal evaporation in high vacuum ( $10^{-6}$  mbar). For the FETs, 40 nm thickness gold (Au) was used for both source and drain, with channel lengths varying between 30 and 100 µm and a constant width of 1000 µm. The Au electrodes were treated with an isopropanol solution of 2,3,4,5,6-pentafluorothiophenol (PFBT, purchased from Sigma-Aldrich) to form a self-assembled monolayer (SAM) prior to deposition of the organic semiconductor. For the LEFET devices, a PFBT SAM coated 40 nm thickness Au film was again used for the source, but 40 nm of Cs<sub>2</sub>CO<sub>3</sub>/Ag was used instead for the drain electrode. The organic semiconductor layer was deposited by spin coating at 2000 rpm for 30 seconds and was then annealed at 120 °C for 15 minutes. CYTOP (~ 900 nm thickness) was next spin-coated (as purchased, CYTOP CTL 809M from AGC Chemicals) as the dielectric layer. Finally, 20 nm of Al was evaporated through a shadow mask to form the top gate electrode. Thicknesses of the dielectric, semiconductor and electrode layers were measured using a Dektak Stylus Profilometer and transistor channel dimensions were checked using an optical microscope (Nikon Eclipse E600).

*Electrical and Optical Characterization:* The electrical and optical characteristics of the devices were measured in a dry nitrogen glovebox using an Agilent B2902A semiconductor parameter analyser and a probe-station fitted with two calibrated photodiodes positioned above and below the active region of the device (13,19). Electroluminescence and Photoluminance spectra were measured using an optical-fiber-coupled Ocean-Optics USB4000-XR spectrometer.

The device luminance was determined from the photodiode photocurrent, which in turn had been calibrated using an OLED pre-measured with a Konica Minolta LS-100 luminance meter. The emission zone area was calculated from the measured intensity profiles of microscopic images of the functioning devices, using the full width at half maximum values. The images were taken using a digital camera attached to the probe station. External quantum efficiency values were calculated using the photocurrent, source-drain current and emission spectrum, under the assumption that emission is Lambertian, as reported previously (13,19,24).

FET and LEFET charge carrier mobilities were determined from the electrical transfer characteristics in the saturation regime, using the following equation:

$$I_{DS} = \frac{W C_i}{2 \times L} (V_{GS} - V_{TH})^2$$

where  $I_{DS}$  is the experimentally measured source drain current, *W/L* is the channel width-tolength ratio,  $V_{GS}$  is the operating gate voltage and  $C_i$  is the geometrical capacitance of the bilayer dielectric. The resulting mobility values were adjusted for the non-ideality of the device characteristics using the reliability factor first proposed by Choi et al. (43), thereby yielding more readily comparable effective mobilities (see **Table S1**, **Supplementary Information**)

*Structural Characterization*: For X-ray diffraction (XRD) measurements, the organic semiconducting materials were spin-coated on heavily doped Si<sup>++</sup> substrates. XRD patterns were obtained from a Rigaku Ultima diffractometer equipped with a Cu anode. Diffractograms were measured for C<sub>8</sub>-BTBT, PDITTTT, and their blend. In order to quantify the XRD data, three prominent (002) diffraction peaks for each sample were fitted by Voigt curves (with both Lorentzian and Gaussian contributions). The Lorentzian broadening relates to the variations in vertical grain size (G<sub>z</sub>), via the standard Scherrer formula, while the Gaussian broadening relates to microstrain ( $\varepsilon_s$ ), which in turn relates to structural defects and the strain field around them (3); as such, the microstrain has been used as a measure of the lateral periodicity of the crystals (3). Note also that the instrumental broadening (< 0.1°) was not taken-into-account in our analysis, so the reported G<sub>z</sub> vales might be slightly overestimated.

Steady-state and time-resolved PL measurements were performed using a time-correlated single-photon counting apparatus (FluoTime 300, PicoQuant GmbH). Polymer and blend films on quartz substrates were excited at 10 MHz frequency using a 405 nm pulsed laser head, with detection wavelength set to 537 nm. The instrument response function (IRF) was taken into consideration in determining the decay times. After measuring the spectrum of excitation laser using a plain substrate, we conduct reconvolution of experimental data with IRF, and we process the biexponential fit to extract decay parameters for each sample.

Solid-state photoluminescence quantum efficiency (PLQE) measurements were performed with a Horiba Scientific FluoroMax-4 Spectrophotometer and Horiba Scientific Quantum- $\varphi$  Integrating Sphere. Directly and Indirectly excited emission spectra were recorded for the samples and a blank substrate at a slit width of 0.9 nm. The PLQE was then calculated using the *de Mello* method (44), with the Jacobian correction applied to all wavelength/energy spectral conversions (45).

## **Supporting Information:**

The Supporting Information is available free of charge on the website at DOI: xxxx or from

the authors.

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#### **Figures and Tables**



**Fig. 1:** Chemical structure of (a) PDITTTT polymer and (c)  $C_8$ -BTBT small molecule. Normalised photoluminescence (PL) and absorption spectra for (b) PDITTTT polymer and (d)  $C_8$ -BTBT: PDITTTT blend films. The solid lines (left ordinate) are absorption and the dashed lines (right ordinate) are the PL, for as spin-coated (black) and for post annealing (blue) thin films.



**Fig. 2:** (a) Normalized time-resolved PL (537 nm, pumped at 405nm) for annealed PDITTTT polymer and C<sub>8</sub>-BTBT: PDITTTT blend films. Topographic AFM images of the (b) polymer only and (c) C<sub>8</sub>-BTBT: PDITTTT blend. Z is the height scale. Root mean square roughness values were determined for each image, with 0.81 nm for the polymer and 1.3 nm for the blend. (d) XRD patterns for PDITTTT polymer (magenta line), C<sub>8</sub>-BTBT (blue line), and their blend (red line). The inset shows details of the (002) basal peak for C<sub>8</sub>-BTBT (blue symbols) and its blend with PDITTTT (red symbols) together with Voigt fits (lines of the same colour). Also shown at the bottom of the panel is a powder diffractogram for C<sub>8</sub>-BTBT with indexing of the peaks based on powder diffraction data (34).



Fig. 3: (a) BC-TG FET architecture using Au/PFBT electrodes. The FET transfer characteristics for the PDITTTT and C<sub>8</sub>-BTBT: PDITTTT blend are given in (b) and (C), where the red line show transfer curves in saturation mode ( $V_{DS}$ = -100V) and black lines in linear regime ( $V_{DS}$ = -20V). The output curves for the PDITTTT and C<sub>8</sub>-BTBT: PDITTTT blend are given in (d) and (e) respectively. The devices had a channel length (L) and width (W) of 50 and 1000 µm, respectively.



**Fig. 4:** (a) BC-TG LEFET architecture. Also shown are the LEFET transfer characteristics (b) for the PDITTTT polymer and (c) C<sub>8</sub>-BTBT: PDITTTT blend. The red line show transfer curves in saturation mode ( $V_{DS}$ = -180V) and black lines in linear regime ( $V_{DS}$ = -30V). The output curves for the PDITTTT and C<sub>8</sub>-BTBT: PDITTTT blend are given in (d) and (e) respectively. The devices had a channel length (L) and width (W) of 140 µm 652 µm, respectively.



**Fig. 5:** (a), (b), (c) and (d) Luminance and EQE voltage dependence for PDITTTT polymer ((a) and (b)) and C<sub>8</sub>-BTBT: PDITTTT blend ((c) and (d)) LEFETs. Data are presented for both top (black lines) and bottom (blue lines) emission. Also shown are (e) microscope emission images and (f) and (g) electroluminescence spectra (black line) for polymer ((f)) and blend ((g)) devices. In (e) the red dashed lines show an outline of the source and drain electrodes. PL spectra (blue lines) are shown in (f) and (g) for comparison with the EL data.

 Table 1: Summary of results and comparison with reported polymer LEFETs: The

 plus/minus values represent the standard deviation on the mean as derived from the

 average of 6 devices.

	This study				<b>Ref #8</b>	Ref #9	<b>Ref #10</b>	<b>Ref #12</b>
	Polymer		Blend		Polymer	Polymer	Polymer	Polymer
Device	3-	3-	3-	3-	3-	3-	3	3-
Architecture	terminal	terminal	terminal	terminal	terminal	terminal	terminal	terminal
	1-layer	1-layer	1-layer	1-layer	1- layer	1- layer	1- layer	1- layer
	Bottom	Тор	Bottom	Тор	Тор	Тор	Тор	Тор
	Emission	Emission	emission	emission	emission	emission	emission	emission
Polymer	PDITTTT		C <sub>8</sub> -BTBT:		PDPPTPT	F8BT	BBTDPP1	PDY-132
Material			PDITTTT :					Super
								Yellow
$\mu_{hole -Sat}$	$0.6\pm0.1$		$7 \pm 1$		$\sim 0.02$	Not	0.1	$1 \times 10^{-4}$
$(cm^2V^{-1}s^{-1})$	$(\mu_{hole - eff} = 0.42)$		$(\mu_{hole - eff} = 3.2)$			given		
(em , s )						<10 <sup>-3</sup>		
$\mu_{electron}$	-	-	-	-	~ 0.02	-	0.09	$4 \times 10^{-4}$
$(\text{cm}^2 \text{V}^{-1} \text{s}^{-1})$						(<10 <sup>-3</sup> )		
<b>ON/OFF</b>	$> 10^{5}$	$> 10^{5}$	$> 10^{3}$	$> 10^{3}$	$> 10^{5}$	< 10	$> 10^{3}$	$< 10^{4}$
Ratio								
Luminance	$\sim 300 \pm$	$\sim 100 \pm$	~ 1600	$\sim 550 \pm$	-	$\sim 4000$	-	~150
$(cd/m^2)$	100	25	$\pm 300$	100				
EQE (%)	$0.035~\pm$	$0.01 \pm$	$0.045 \pm$	$0.01 \pm$	$\sim 0.07$	4	$\sim 10^{-5}$	0.14
	0.01	0.002	0.01	0.02				

# Supporting Information for

# Polymer light-emitting transistors with charge carrier mobilities exceeding

# $1 \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$

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Fig. S1. PL and absorbance spectra of the C<sub>8</sub>-BTBT film.

## **Measurement of PLQE**

Fig. S2. PLQE and Absorption against sample composition.

Table-S1. Numerical values of PLQE & Absorption and integration ranges used to determine

P (emission) and L (excitation) areas.

Fig. S3. Integration ranges used to determine P (emission) and L (excitation) areas.

Fig. S4. Refractive index vs. wavelength of as-spun and annealed polymer film.

**Fig.S5.** Refractive index vs. wavelength of as-spun and annealed small molecule (C<sub>8</sub>-BTBT) film.

Fig. S6. Refractive index vs. wavelength of as-spun and annealed C<sub>8</sub>-BTBT:PDITTTT film.

Fig. S7. Times resolved PL of annealed PDITTTT film.

Fig. S8. Times resolved PL of annealed C<sub>8</sub>-BTBT:PDITTTT film.

Figure S9. Height histograms of the AFM images provided in Figure 2.

## Calculation of Reliability factor and effective mobility

**Table S2.** Calculated mobility, reliability factor and corresponding effective mobility

Fig.S10. Dark-current densities and SCLC fitting in electron-only diode structure.

Fig. S11. Transmittance of bottom glass and top gate electrode.

Fig. S12. Luminance and EQE as function of current density of PDITTTT LEFETs.

Fig. S13. Luminance and EQE as function of current density of C<sub>8</sub>-BTBT:PDITTTT LEFET.

Fig.S14. Image intensity profile and FWHM of PDITTTT LEFETs.

Fig. S15. Image intensity profile and FWHM of C<sub>8</sub>-BTBT:PDITTTT LEFETs.

Fig. S16. Working mechanism.

Table-S3. Recombination Efficiencies.

Table S4. Comparison of single-layer polymer and small molecule based LEFETs.

Figure S17. Normalized LEFET Source drain current and luminance vs. storage time. References



Figure S1. Absorbance (normalized to absorption peak at 359 nm) and PL spectra of  $C_8$ -

BTBT film.

## <u>Measurements of Photoluminescence Quantum Efficiency (PLQE):</u> The de Mello method [39] involves recording three spectra to calculate PLQE:

1. Blank: No sample placed in sphere and excitation beam placed in indirect position.

Indirect Excitation: Sample placed in sphere away from the first pass of the excitation beam. Any emission is due to absorption of the reflected excitation beam.

Direct Excitation: Sample placed in sphere directly in the path of the excitation beam. Emission due to absorption from this direct excitation as well as any absorption from reflections.

Figure S8. Integrating sphere experiments required to calculate PLQE using the de Mello method.

The absorption, A, and PLQE were calculated using equations (1) & (2), where L is the area under the excitation peak and P is the area under the emission peak for the denoted experiment. To determine these L and P values, the spectra were baselined and converted to Energy with the Jacobian correction applied (2).

$$A = 1 - \frac{L_3}{L_2}$$
(1)  
$$PLQY = \frac{P_3 - (1 - A)P_2}{L_1 A}$$
(2)

A = absorption of sample, P2 = area under indirect emission peak, P3 = area under direct emission peak, L1 = area under blank excitation peak, L2 = area under indirect excitation peak, L3 = area under direct excitation peak



Figure S2. PLQE and absorption against sample composition (percentage fraction of polymer, PDITTTT).

**Table-S1**. Numerical values of PLQE & Absorption and integration ranges used to determine

 P (emission) and L (excitation) areas.

				Integration Ranges (eV)			
C <sub>8</sub> BTBT:P	% PDITTTT	А	PLQE	Excitation	Excitation	Emission	Emission
DITTTT				Low	High	Low	High
3:1	25	0.30	10.3%	2.427	2.567	2.081	2.422

1:1	50	0.53	10.1%	2.441	2.541	2.046	2.436
1:3	75	0.69	13.3%	2.441	2.541	2.046	2.436
0:1	100	0.78	11.7%	2.441	2.541	1.968	2.436



Figure S3. Integration ranges used to determine P (emission) and L (excitation) areas.



Figure S4. Refractive index vs. wavelength of as-spun and annealed polymer film.



Figure S5. Refractive index vs. wavelength of as-spun and annealed small molecule (C $_8$ -BTBT) film.



**Figure S6.** Refractive index vs. wavelength of as-spun and annealed C<sub>8</sub>-BTBT:PDITTTT film.



Figure S7. Times resolved PL of annealed PDITTTT film.



Figure S8. Times resolved PL of annealed C8-BTBT:PDITTTT film.



Figure S9. Height histograms of the AFM images provided in Figure 2.

## **Calculation of reliability factor and effective mobility:**

The measurement reliability factor\* 'r' is determines the behaviour of reported FETs follows the physics of the simple linear increase of conductivity with carrier density under the assumption of a constant mobility and negligible threshold voltage. It is defined as the ratio of the maximum channel conductivity experimentally achieved in a FET at the maximum gate voltage to the maximum channel conductivity expected in a correctly functioning ideal FET with the calculated carrier mobility  $\mu$  and identical other device parameters at the same maximum gate voltage. Reliability factor, "r" can be calculated from the calculated " $\mu$ ", the stated device parameters and the FET characteristics. In the saturation regime, equation (3) shows that the reliability factor is:

$$r_{sat} = \frac{\left[\frac{\sqrt{|I_{SD}|^{max}} - \sqrt{|I_{SD}|^{0}}}{|V_{GS}|^{max}}\right]^{2}}{\left[\frac{WC_{i}}{2L} \mu_{sat}\right]_{calculated}}$$
$$= \frac{\left[\frac{\sqrt{|I_{SD}|^{max}} - \sqrt{|I_{SD}|^{0}}}{|V_{GS}|^{max}}\right]^{2}}{\left[\frac{\partial\sqrt{|I_{SD}|}}{V_{GS}}\right]^{2}_{calculated}}$$
(3)

Here,  $\mu_{sat}$  is the calculated mobility, *L*, *W* and *C*<sub>i</sub> are the device parameters, and  $|I_{SD}|^{max}$  is the experimental maximum source–drain current reached at the maximum gate voltage  $|V_{GS}|^{max}$ . And  $|I_{SD}|^{0}$  denotes the source–drain current at  $V_{GS} = 0$ .

The effective mobility is calculated from the reliability factor, where reliability factor is 100%. The effective mobility can be also calculated from reliability factor and claim mobility from the equation (4),

$$\mu_{eff} = r \, x \, \mu_{calculated} \tag{4}$$

Table-S2. Calculated mobility, reliability factor and effective mobility calculation.

Devices	$\mu_{sat}$ (cm <sup>2</sup> V <sup>-1</sup> s	μeff (cm <sup>2</sup>		
		<b>µ</b> calculated	r %	V <sup>-1</sup> s <sup>-1</sup> )
PDITTTT	OFET	1	63 %	0.63
	LEFET	0.6	70 %	0.42
C <sub>8</sub> BTBT:PDITTTT	OFET	1.6	51 %	0.82
	LEFET	7	56 %	3.2

## **Measurement of electron mobility:**

Electron mobilities were measured space charge limiting current (SCLC) formulation using a diode configuration of glass/Al/Cs<sub>2</sub>CO<sub>3</sub>/(polymer or blend)/Cs<sub>2</sub>CO<sub>3</sub>/Al. By taking the dark current density in the range of 0-8 V and fitting the results to a space charge limited equation (5).

$$J = \frac{9 \epsilon_o \epsilon_r \mu_o V^2}{8 L^3} exp\left(0.89\beta \sqrt{\frac{V}{L}}\right)$$
(5)

where *J* is the current density, *L* is the film thickness of the active layer,  $\mu_o$  is the hole mobility,  $\varepsilon_r$  is the relative dielectric constant of the transport medium,  $\varepsilon_o$  is the permittivity of free space (8.85×10<sup>-12</sup> F/m), V (= V<sub>appl</sub> – V<sub>bi</sub>) is the internal voltage in the device, where V<sub>appl</sub> is the applied voltage to the device and V<sub>bi</sub> is the built-in voltage due to the relative work function difference of the two electrodes.



**Figure S10.** Dark-current densities and SCLC fitting in electron-only diode structure using: (a) neat films; b) blend films. The solid red lines represent the best fits to SCLC model and the open circles/squares are the experimental data. Extracted mobilities from the fitting were 5.6  $\times 10^{-8}$  cm<sup>2</sup> V<sup>-1</sup> s<sup>-1</sup> in polymer PDITTTT films 6  $\times 10^{-8}$  cm<sup>2</sup> V<sup>-1</sup> s<sup>-1</sup> in blend C<sub>8</sub>-BTBT:PDITTTT films.



Figure S11. Transmittance of bottom glass and top Al gate electrode.



Figure S12. Luminance and EQE as function of current density of polymer LEFETs.



Figure S13. Luminance and EQE as function of current density of blend LEFETs.



Figure S14. Image intensity profile and FWHM of polymer PDITTTT based LEFETs.



Figure S15. Image intensity profile and FWHM of C<sub>8</sub>-BTBT:PDITTTT based LEFETs.



Figure S16. (a) Working mechanism of the LEFET, where LEP is light emitting polymer films (pristine or blend) and (b) energy level diagram.

## **Calculating recombination efficiency (internal quantum efficiency):**

Electrons and the holes are injected from source and drain electrodes and move across the FET channel under the influence of the lateral source-drain electric field. These moving charges are probable to form singlet state excitons and triplet state excitons and eventually recombine to emit light. The efficiency of light emission is given by equation 6:

$$\varphi_{EQE} = \varphi_{escape} \times \varphi_{capture} \times \varphi_{spin} \times \varphi_{PLQE}$$
(6)

where  $\varphi_{capture}$  (recombination efficiency) is the fraction of electrons and holes that recombine to form excitons,  $\varphi_{EQE}$  is the calculated EQE,  $\varphi_{escape}$  is the fraction of photons that can escape from the device,  $\varphi_{spin}$  is the factor allowed due to spin statistics and  $\Phi_{PLQE}$  is the photoluminescence quantum yield (PLQE) in the solid state. The percentage of photons that can escape from device,  $\varphi_{escape}$ , is approximately  $1 / 2n^2$  (where n is the refractive index of the polymer film is 2.2 and blend films is 1.95 at peak emission wavelength). Polymer is a singlet emitter and so  $\varphi_{spin} = 0.25$ . Calculated recombination efficiency for all the devices is given below in **Table-S3**.

Table-S3. Recombination Efficiencie	es.
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Parameters	Polymer	Blend
PLQE	11.7 %	13.3 %
EQE at maximum brightness [%]	0. 035 %	0.045 %
Recombination Efficiency at maximum brightness [%]	5.8 %	5.1 %

EQE at maximum emission intensity (%)	ON/OFF Ratio	μ <sub>ekctron</sub> (cm <sup>2</sup> V <sup>-1</sup> s <sup>-1</sup> )	μ <sub>hole</sub> (cm²V <sup>-1</sup> s <sup>-1</sup> )	Material	Architecture	Device	
0.046	~106	ı	1	Polymer	1-layer	3 terminal	ТЫ
0.04	~10 <sup>6</sup>		1	Polymer Blend	1-layer	3 terminal	s study
0.003	~109	-	6	BTBT-C <sub>10</sub>	1-layer	3 terminal	Ref#1
0.0006	~107		2	Ph-BTBT-C <sub>10</sub>	1-layer	3 terminal	Ref#1
4	<10	- (<10 <sup>-3</sup> )	(<10 <sup>-3</sup> )	F8BT	1- layer	3 terminal	Ref #2
0.002 & 0.02	~10 <sup>2</sup> & ~10 <sup>5</sup>	0.27 & 0.12	0.82 & 2.3	rubrene & tetracene (single crystals)	1- layer	3-terminal	Ref#3
Not reported	~104	1	6 × 10 <sup>-6</sup>	EFIN	1-layer	3-terminal	Ref #4
Not reported	<104	1×10 <sup>-2</sup>	1×10 <sup>-4</sup>	BSB-Me (single crystal)	1-layer	3-terminal	Ref#5
Not reported	<104	1.3×10 <sup>-2</sup>	1.1×10 <sup>-1</sup>	P3V2 (single crystal)	1-layer	3- terminal	Ref #6
0.14	<104	4×10 <sup>-4</sup>	1×10 <sup>-4</sup>	SY	1- layer	3 terminal	Ref#7

Table-S4. A comparison of the results of single-layer LEFETs previously reported and this study.



**Figure S17.** Normalized Source drain current (black circles) and luminance ratio (red circles) of (**a**) PDITTTT and (**b**) C<sub>8</sub>-BTBT:PDITTTT films based LEFET. Samples were stored in ambient for a week and tested.

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